


<b>Search Notes</b>  	<b>Application/Control No.</b>  10802914	<b>Applicant(s)/Patent Under Reexamination</b>  FUNAHASHI ET AL.
	<b>Examiner</b>  Rutz, Jared I	<b>Art Unit</b>  2187

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
text and text limited classification search in EAST, see search history	3/14/07	jir
consulted Kevin Ellis	3/13/07	jir
consulted Brian Peugh	3/14/07	jir

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner